

# ***Dynamic Interferometry: Applications of High Speed Interferometry***

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4D Technology Corporation

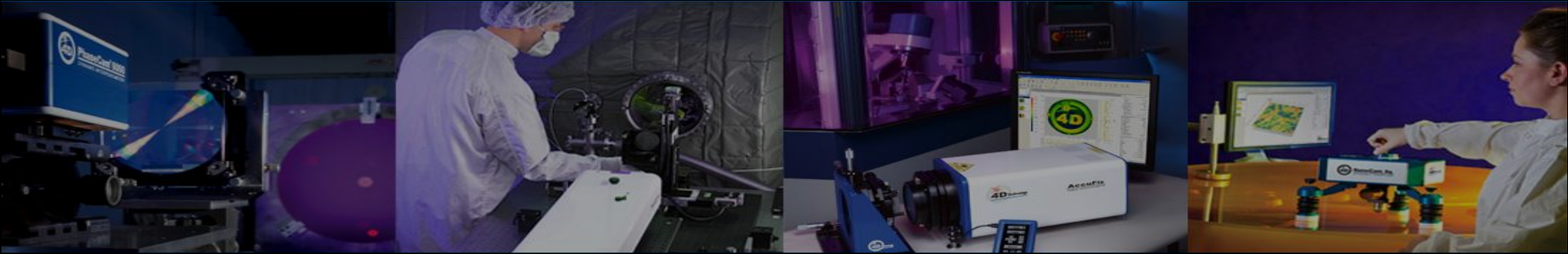


Mirror Tech Days 2017



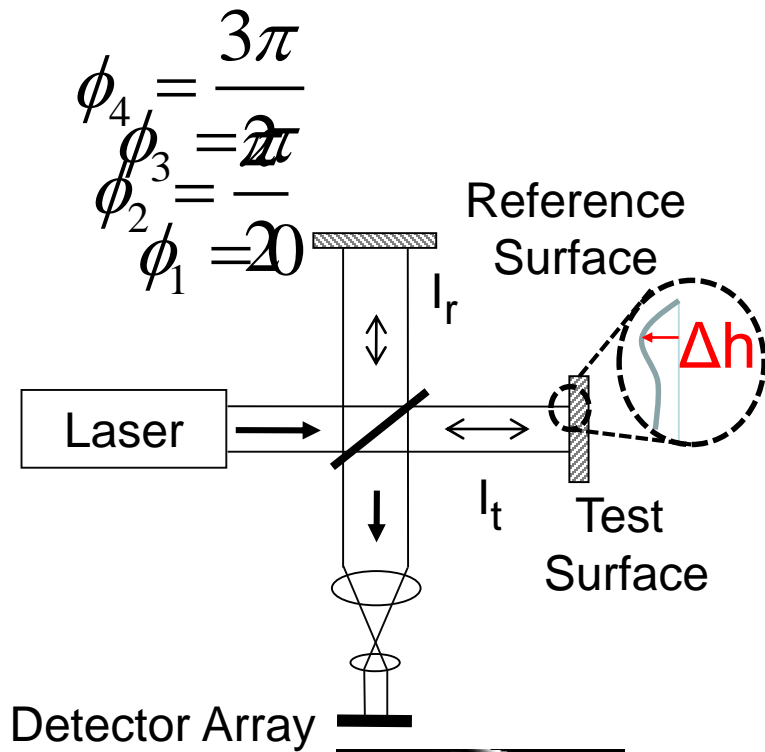
# Outline

- ▶ Dynamic Interferometry
- ▶ High Speed Interferometer
- ▶ JWST Testing
- ▶ Beyond JWST
  - ▶ Combine High Speed with ESPI
  - ▶ New Interferometer Status



# Dynamic Interferometry

# Temporal Phase-Shift Interferometry



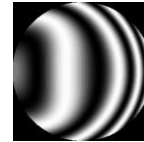
$$I_n = I_T(1 + \gamma \cos(\phi + \phi_n))$$

$$\phi = 4\pi \frac{\Delta h}{\lambda}$$

$$\gamma = 2 \sqrt{(I_t \cdot I_r) / (I_t + I_r)}$$



$$I_1 = I_T(1 + \gamma \cos(\phi))$$



$$I_2 = I_T(1 + \gamma \sin(\phi))$$

is it a hill or valley?



reflectivity or surface?

$$I_3 = I_T(1 - \gamma \cos(\phi))$$



$$I_4 = I_T(1 + \gamma \sin(\phi))$$

Detector Array

$$I_3(x, y)$$

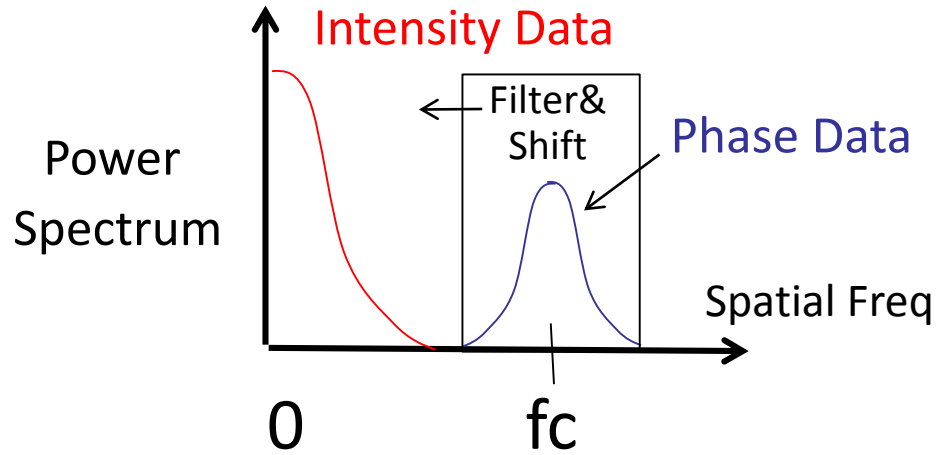
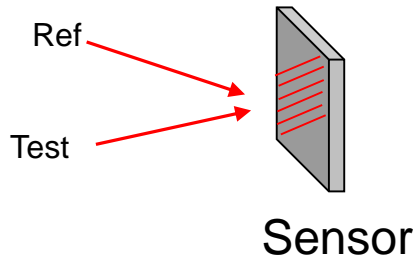


**120 milliseconds for acquisition**

$$\tan(\phi(x, y)) = \frac{I_4(x, y) - I_2(x, y)}{I_3(x, y) - I_1(x, y)}$$

$$\text{Height}(x, y) = \frac{\lambda}{4\pi} \phi(x, y)$$

# Spatial Carrier Dynamic Sensor

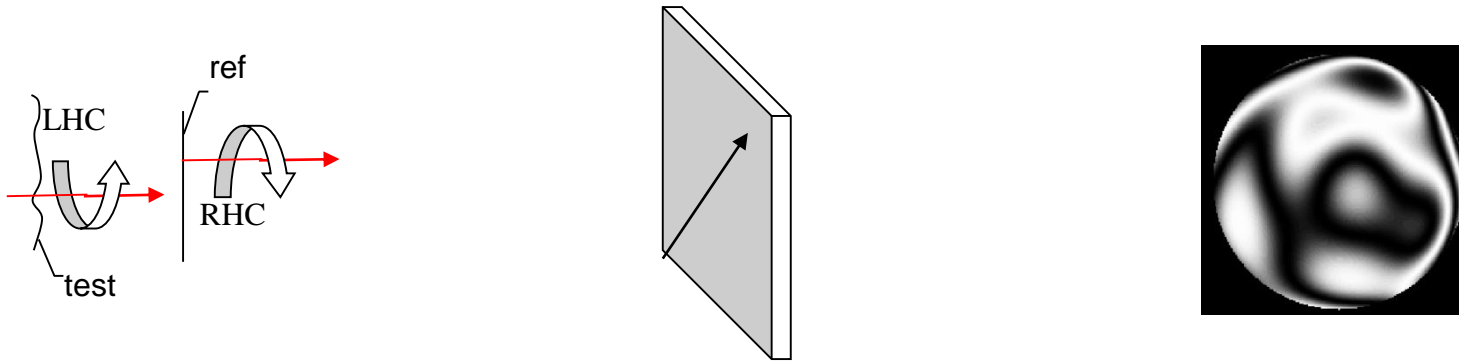


- ▶ Convenient to implement
- ▶ FT or convolution approach
- ▶ Off-axis beams – can cause retrace
  - Requires calibration
    - $\lambda/10$  flats special optics
    - Special Data Processing

M. Kuchel, "The new Zeiss interferometer," SPIE Vol. 1332 Optical Testing and Metrology III: Recent Advances in Industrial Optical Inspection, p655-663, 1990

# Polarization Phase Shift Method

Use polarizer as phase shifter

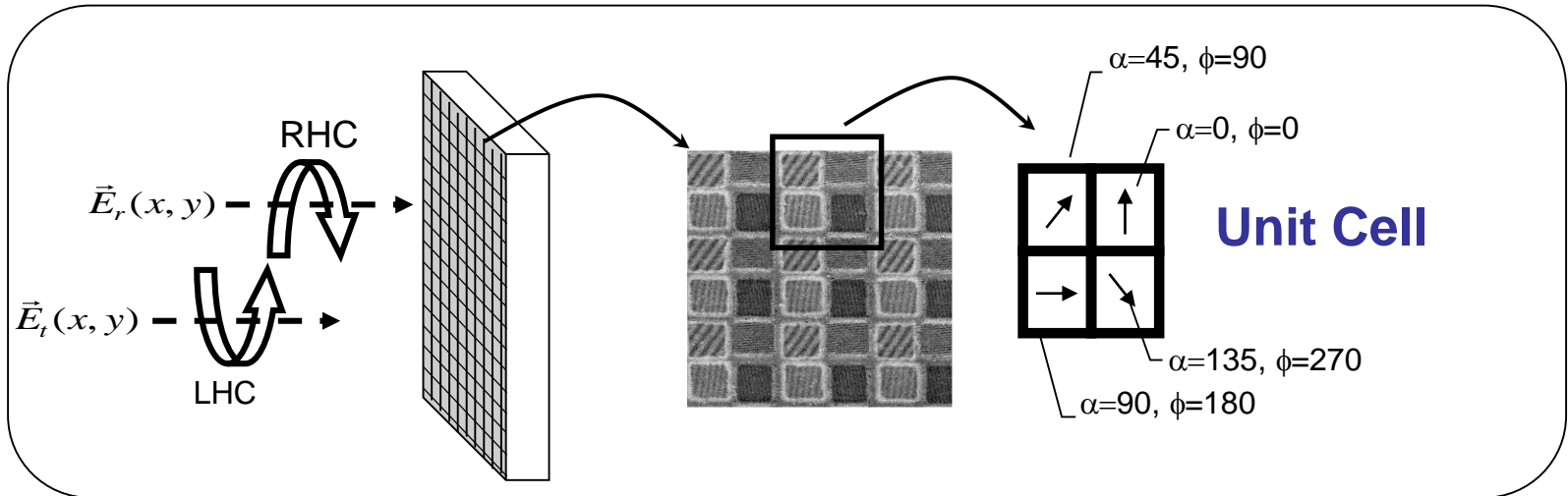


Circular polarized beams ( $\theta$ ) + linear polarizer ( $\alpha$ )  $\Rightarrow I = I_T(1 + \gamma \cos(\theta + 2\alpha))$

Phase-shift depends on polarizer angle

Kothiyal and Delsile, (1985)

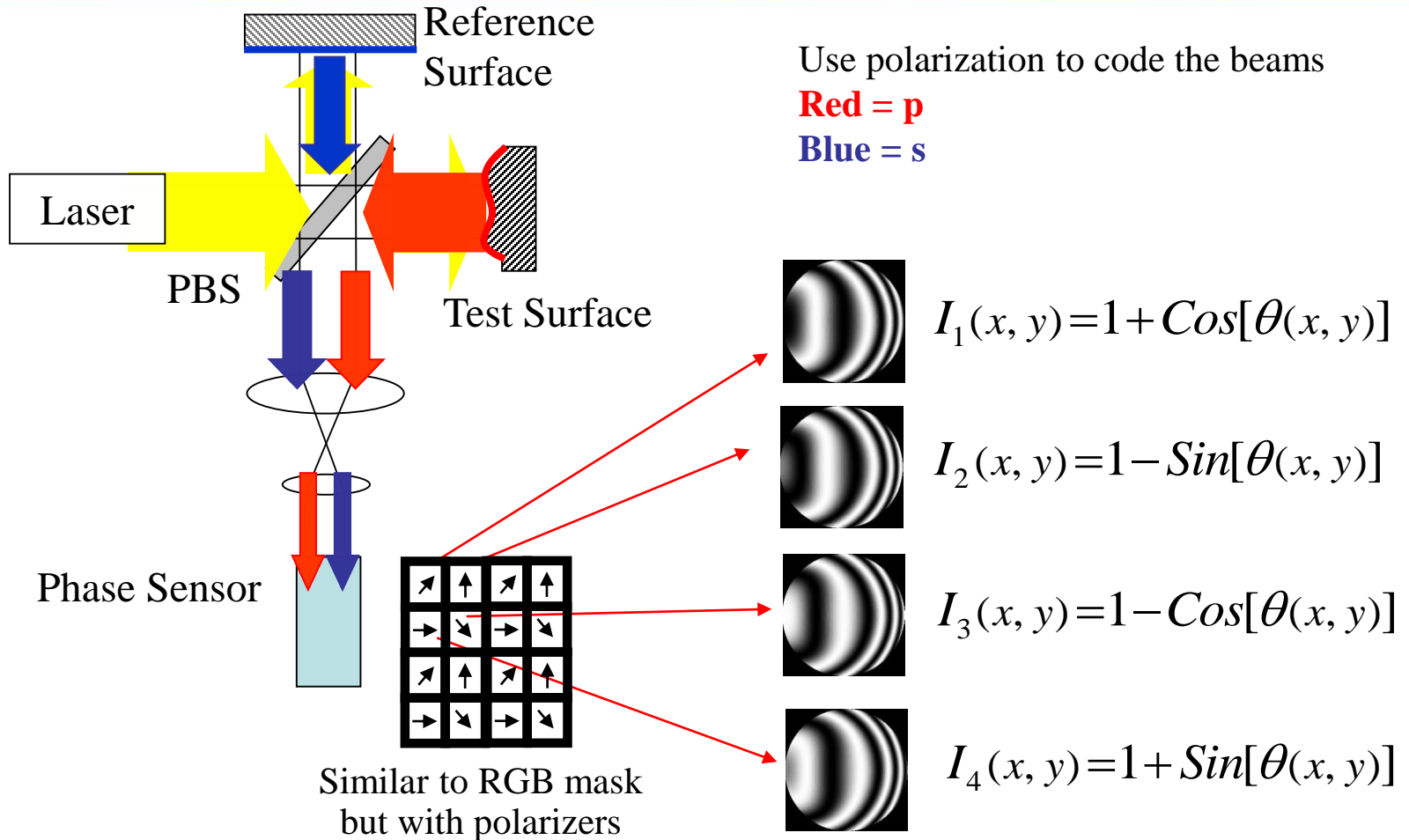
# Simultaneous polarization phase-shift – micro-polarizer camera



- ▶ Array of oriented micropolarizers
  - ▶ Similar to RGB color mask
  - ▶ On-axis imaging, broadband wavelength
- ▶ **Dynamic Interferometry™**  
“Precision measurement in dynamic environments”

US Patent 7,230,719 (2004)

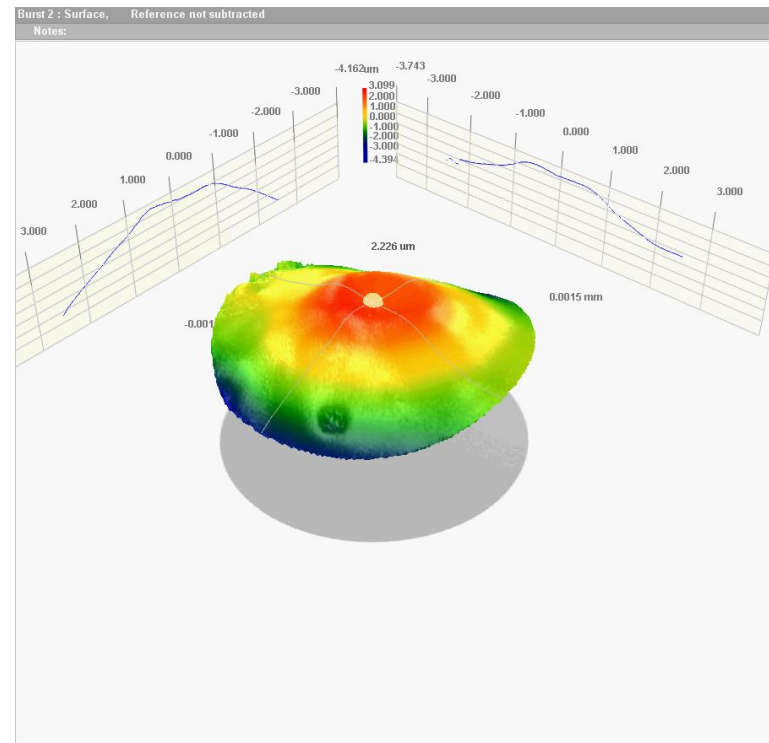
# Dynamic Interferometry

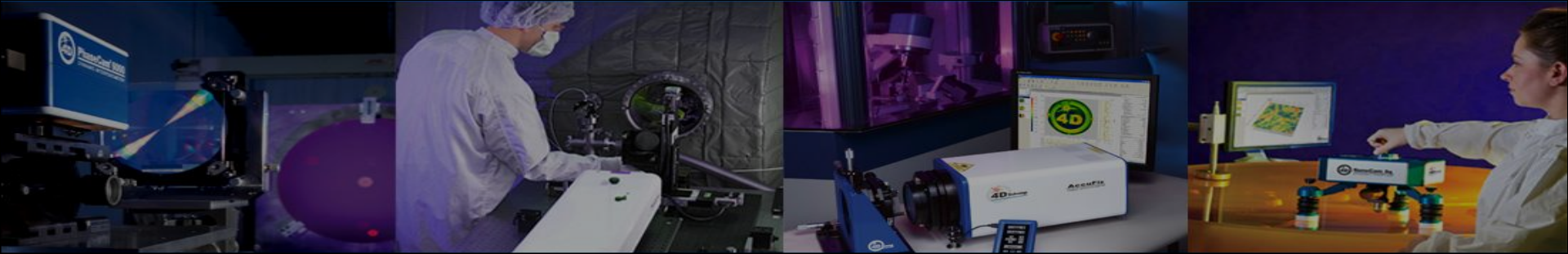


**Nanoseconds for acquisition!**



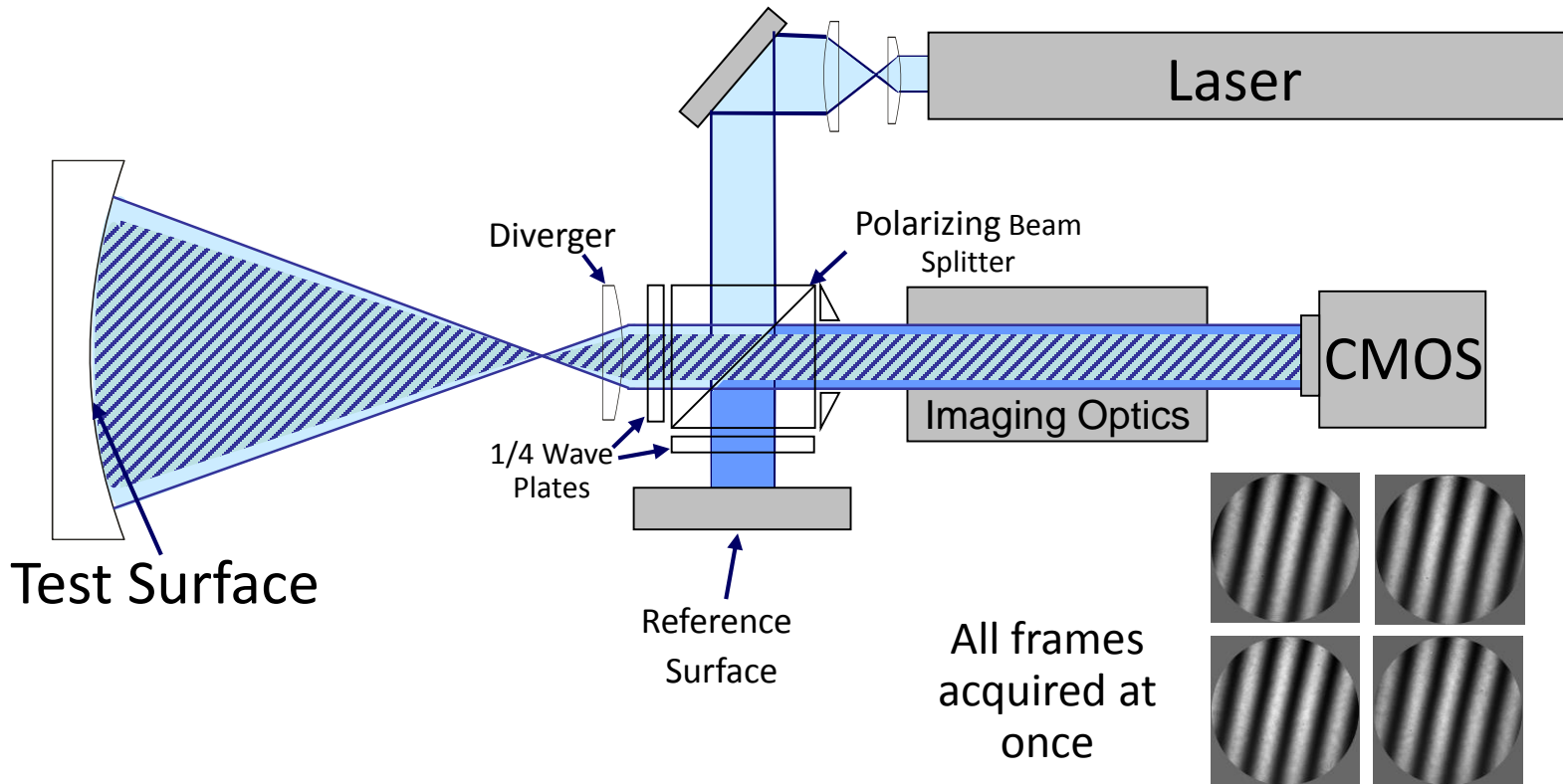
# Dynamic Measurement of Human Eye





# High Speed Interferometer

# High Speed Twyman-Green



On-axis imaging – works well with fast optics, zoom



# Frame Rate Vs FOV

Frame Size	Frame Rate (fps)
1024 x 1024	500
640 x 480	1,800
400 x 300	4,000

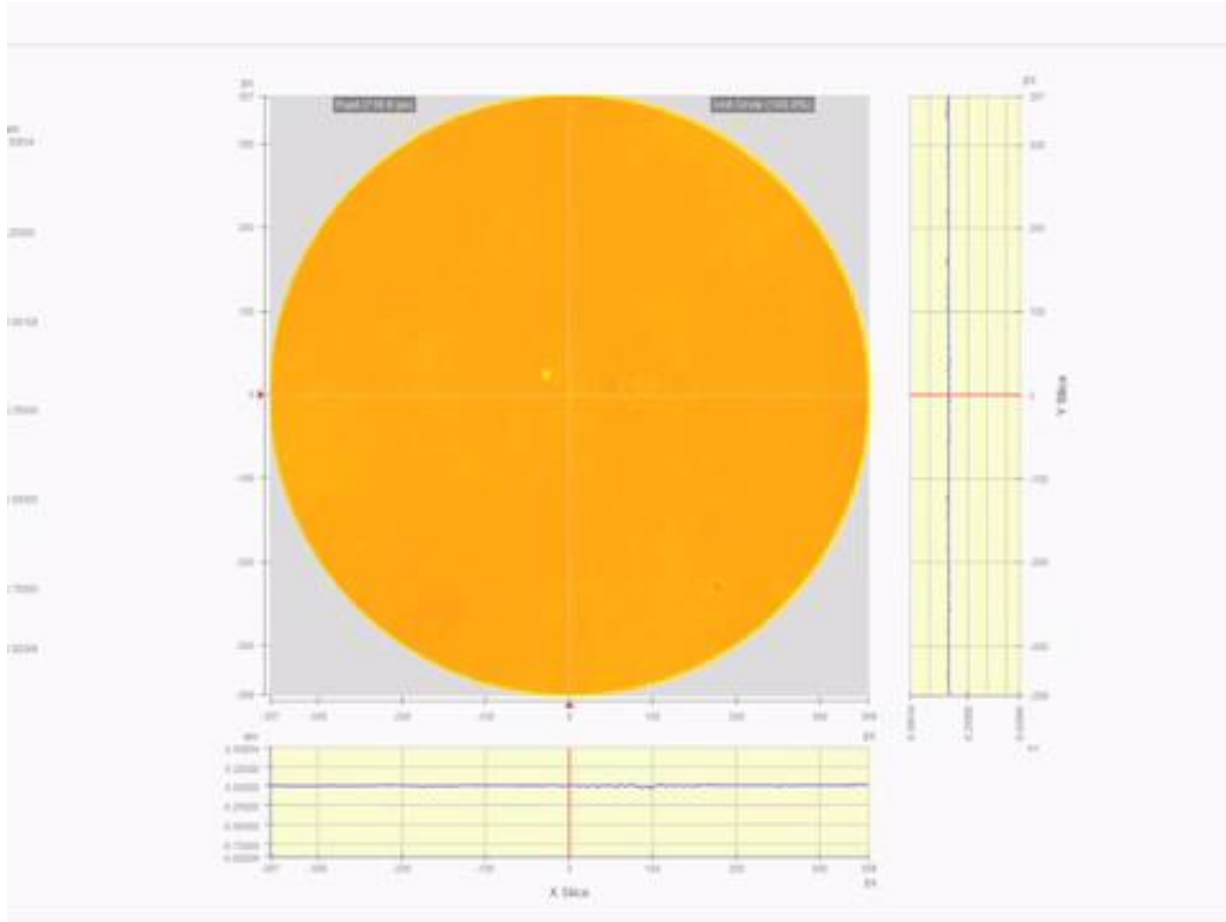
Frame rates greater than 10,000 fps  
achievable with smaller FOV



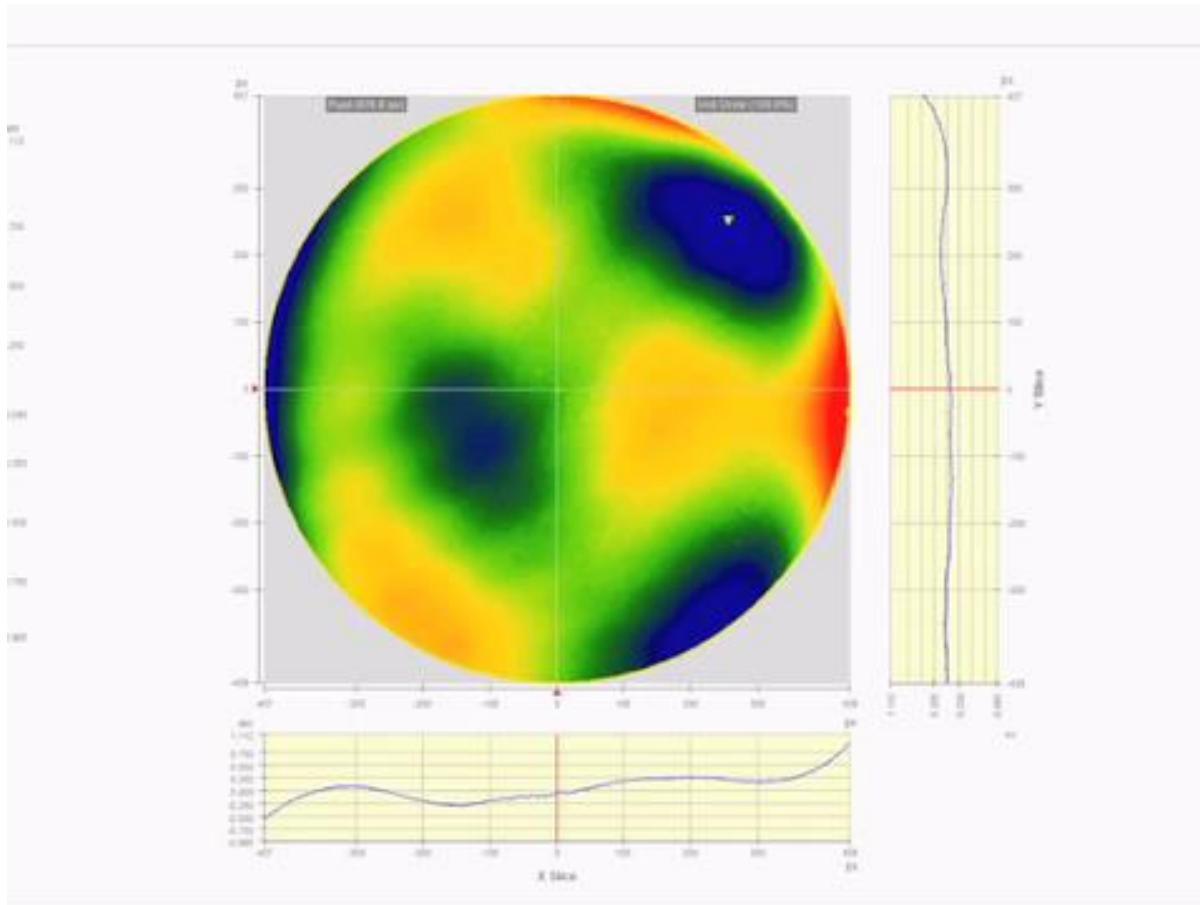
# *High-Speed Interferometer Capture Limits*

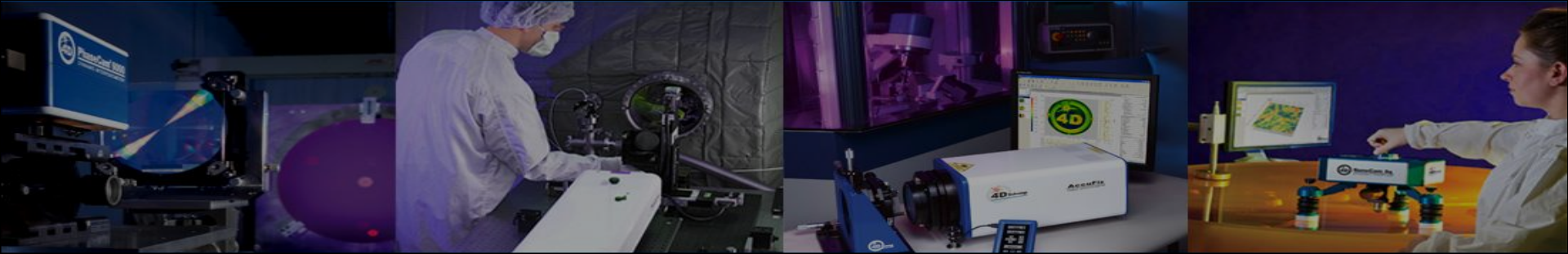
- ▶ Data typically collected for 10 seconds for each measurement.
- ▶ For each measurement approximately 4.2 GB of data collected.
- ▶ The limit on how long a measurement can run is determined by the amount of memory in the data acquisition computer, 20 GB in this instance.

# Air Stream, 525 Frames/Second



# Water Surface, 525 Frames/Second





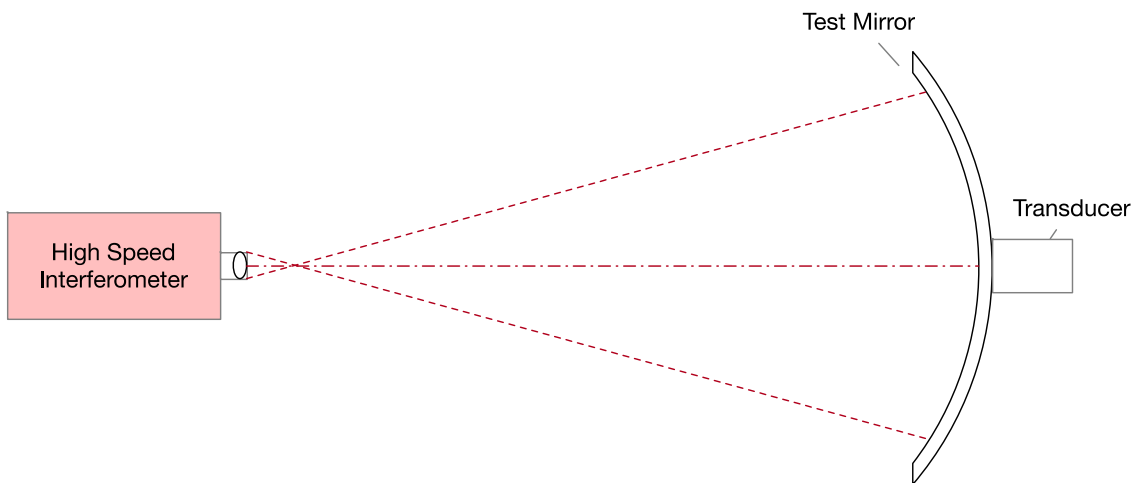
# JWST Measurements



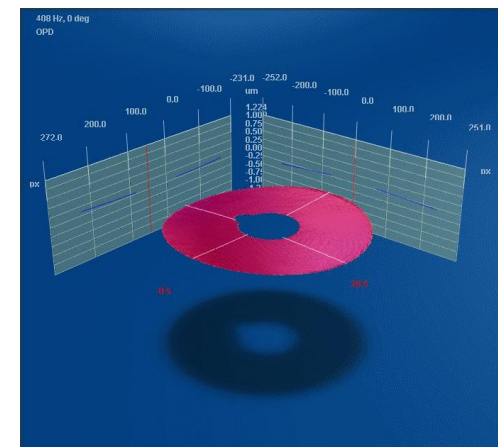


# Vibrational Strain Measurements

- ▶ Vibrational measurements can validate structural modeling and ensure good performance in flight
- ▶ Exo-planet imaging will require extreme stability
- ▶ 5000 fps dynamic interferometer used to characterize vibration

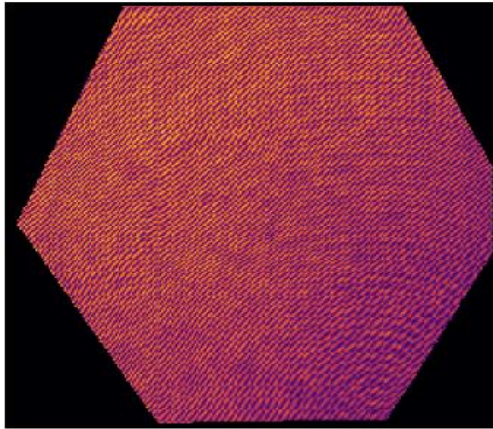


*Mirror excited at 400Hz*

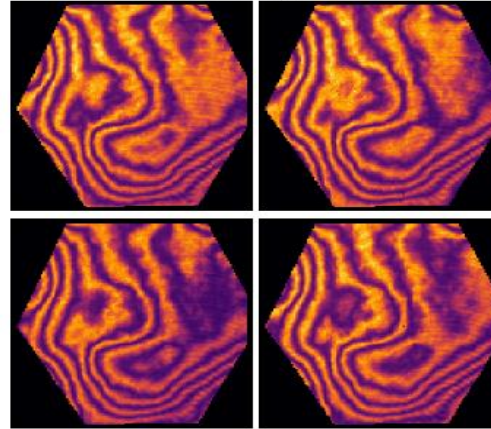


# Single High Speed Interferometer Measurement

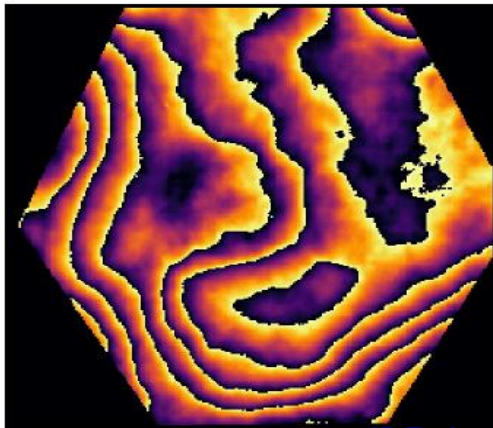
Raw Frame



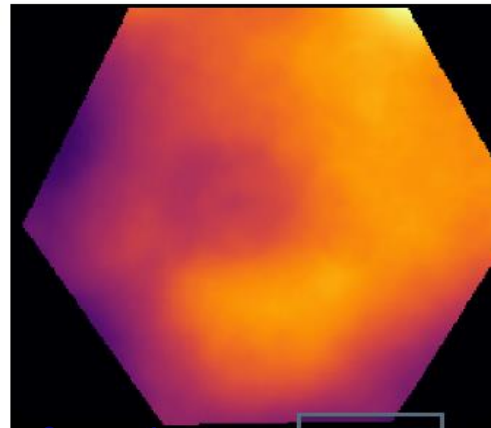
Instantaneous Phase-Shifted Interferograms

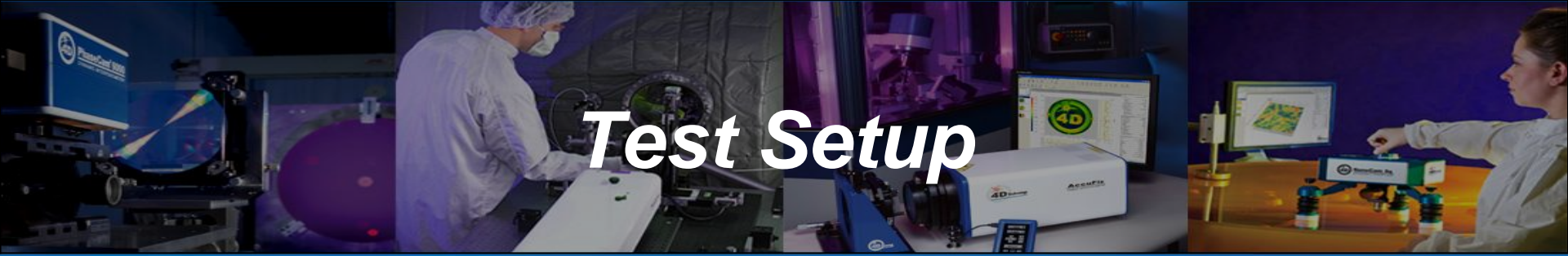


Reconstructed Wrapped Phase

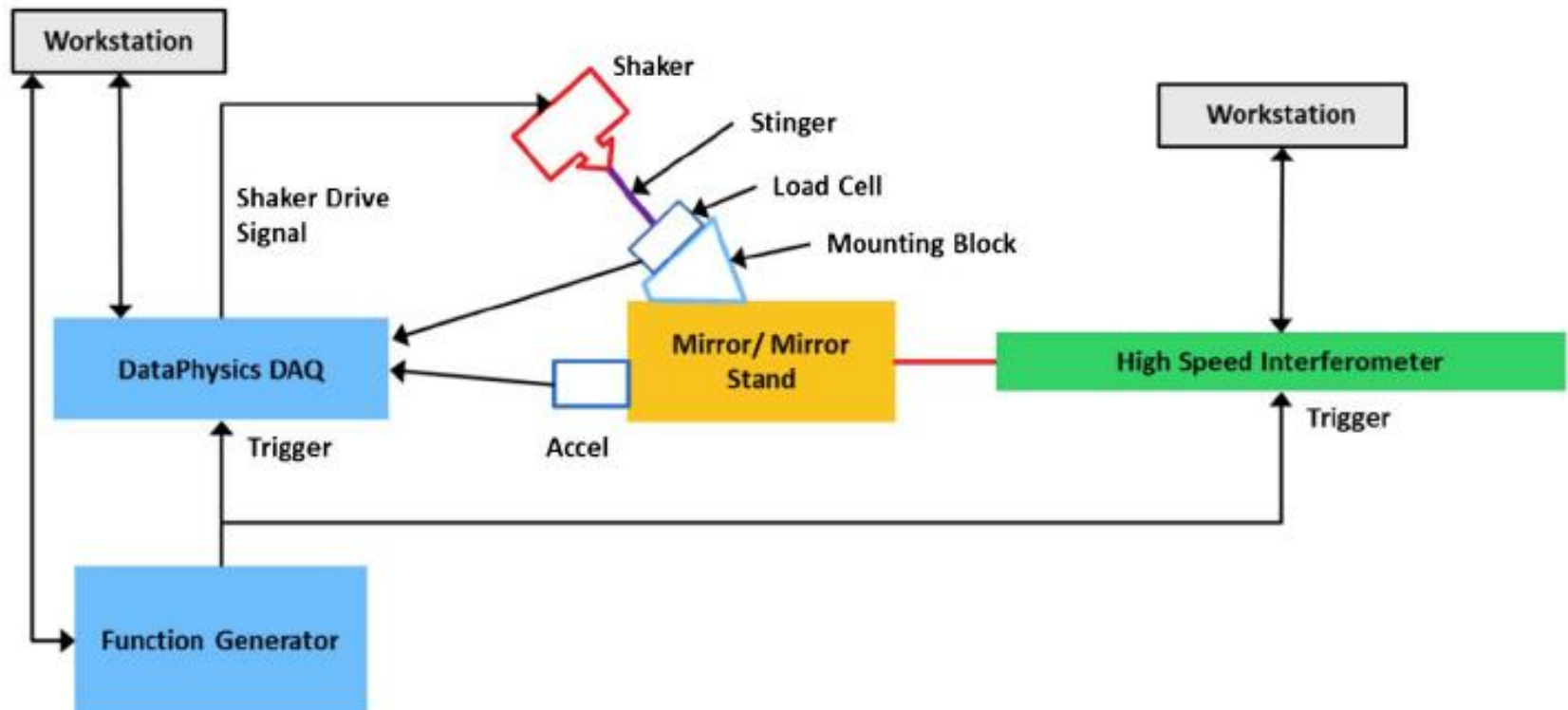


Surface





# Test Setup



# Vibrational Strain Measurements - JWST



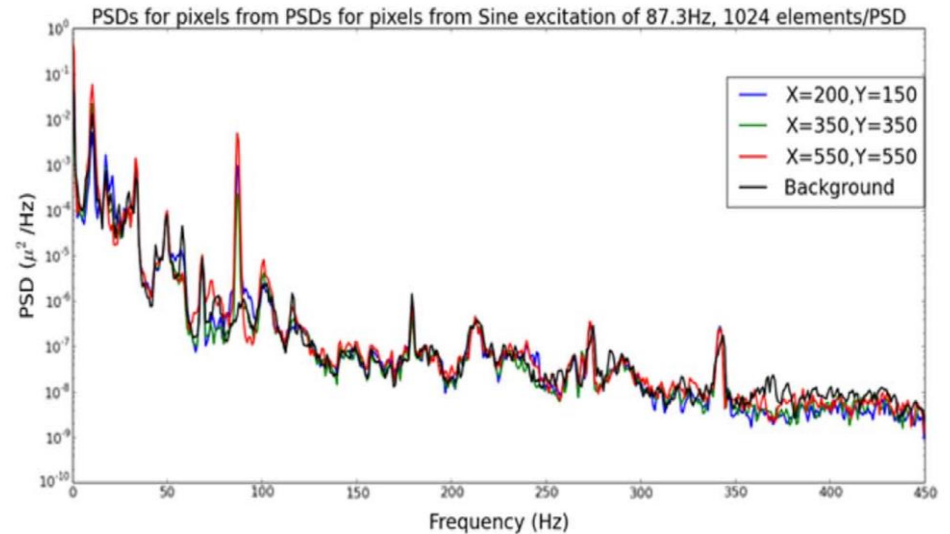
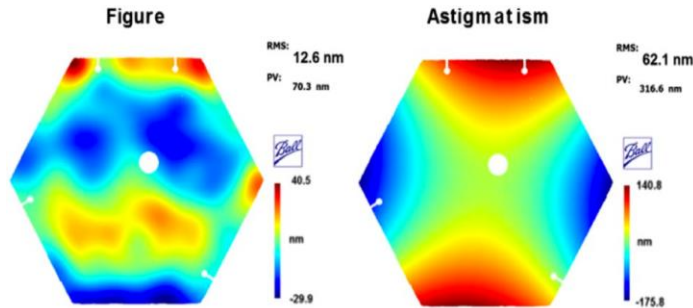
COMPARISON OF SSDIF MEASUREMENT TO XRCF MEASUREMENT

SSDIF compensated for:

- RoC actuation residual

XRCF compensated for:

- gravity tilt on test stand
- reference sphere measurement
- window vacuum effects
- CGH substrate error
- RoC actuation residual
- CGH to mirror spacing error

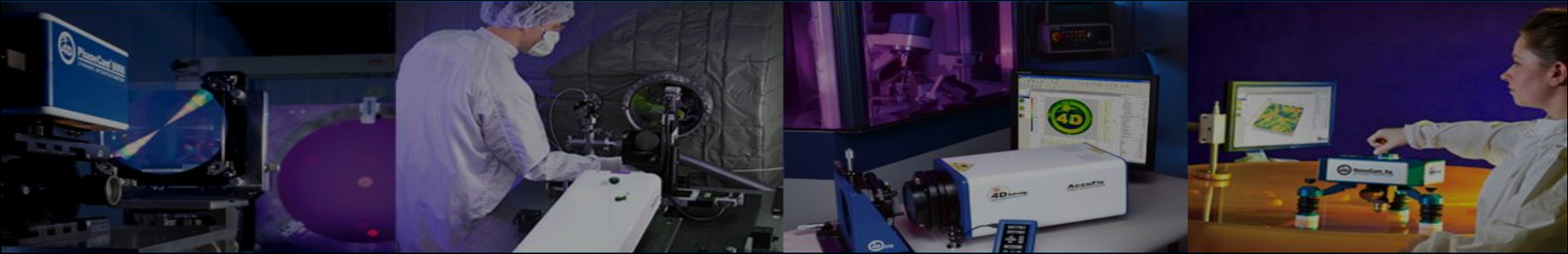


Saif, et al., "Nanometer level characterization of the James Webb Space Telescope opto-mechanical systems using high-speed interferometry," Appl. Opt. 54 (2015)



# Measurement Results

- ▶ Interferometer is capable of tracking large absolute motion (i.e., piston) of the mirror's entire surface over orders of magnitudes of wavelengths displacement.
- ▶ Preliminary tests have shown it to be capable of measuring dynamic effects on the level of tens of picometers reliably.
- ▶ This measurement capability is very important for future space optics and an interferometer combining the high speed capability and the ESPI is currently being designed and constructed.



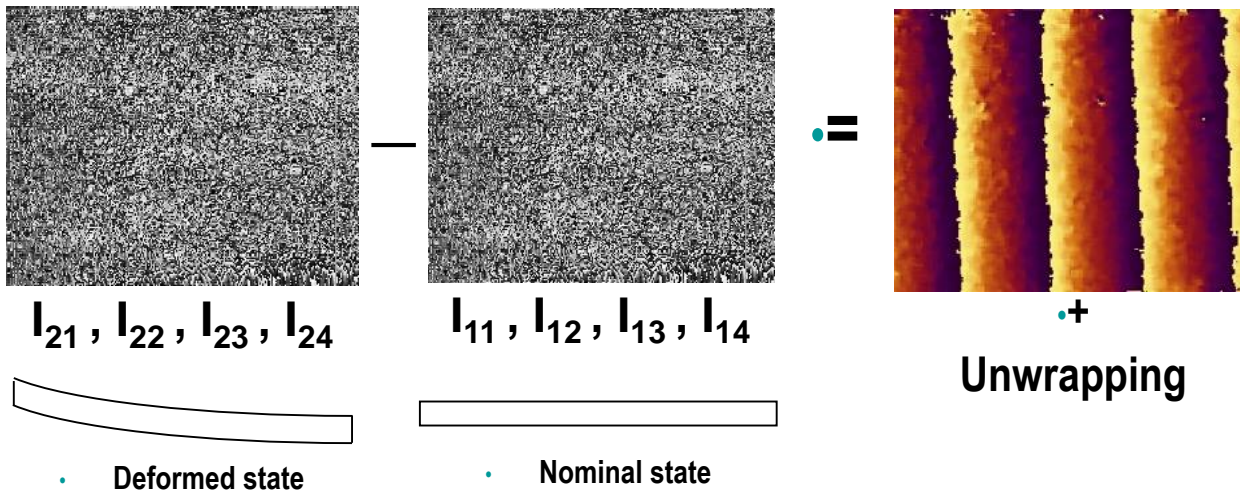
# Beyond JWST – Combine High Speed Interferometer with ESPI

# James Webb Space Telescope Back Structure





# ESPI Measures Changes In Diffuse Structures



$$DOPD = \frac{I}{2\rho} \text{ArcTan} \left( \frac{[I_{23} - I_{21}][I_{14} - I_{12}] + [I_{11} - I_{13}][I_{24} - I_{22}]}{[I_{11} - I_{13}][I_{21} - I_{23}] + [I_{14} - I_{12}][I_{24} - I_{22}]} \right)$$

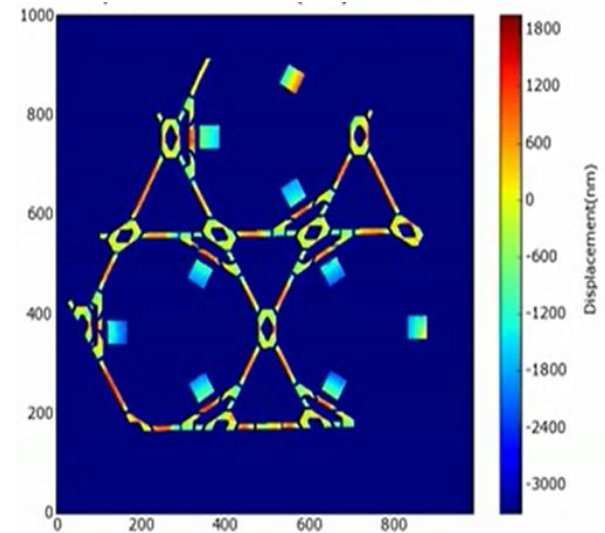
**Provides differential measurement of diffuse and specular surfaces.**

# Structural/Thermal Strain Measurements

- ▶ Thermal response of structure key in maintaining alignment in space.
- ▶ Speckle interferometry – change in shape of diffuse structures.
- ▶ Requires significant laser power

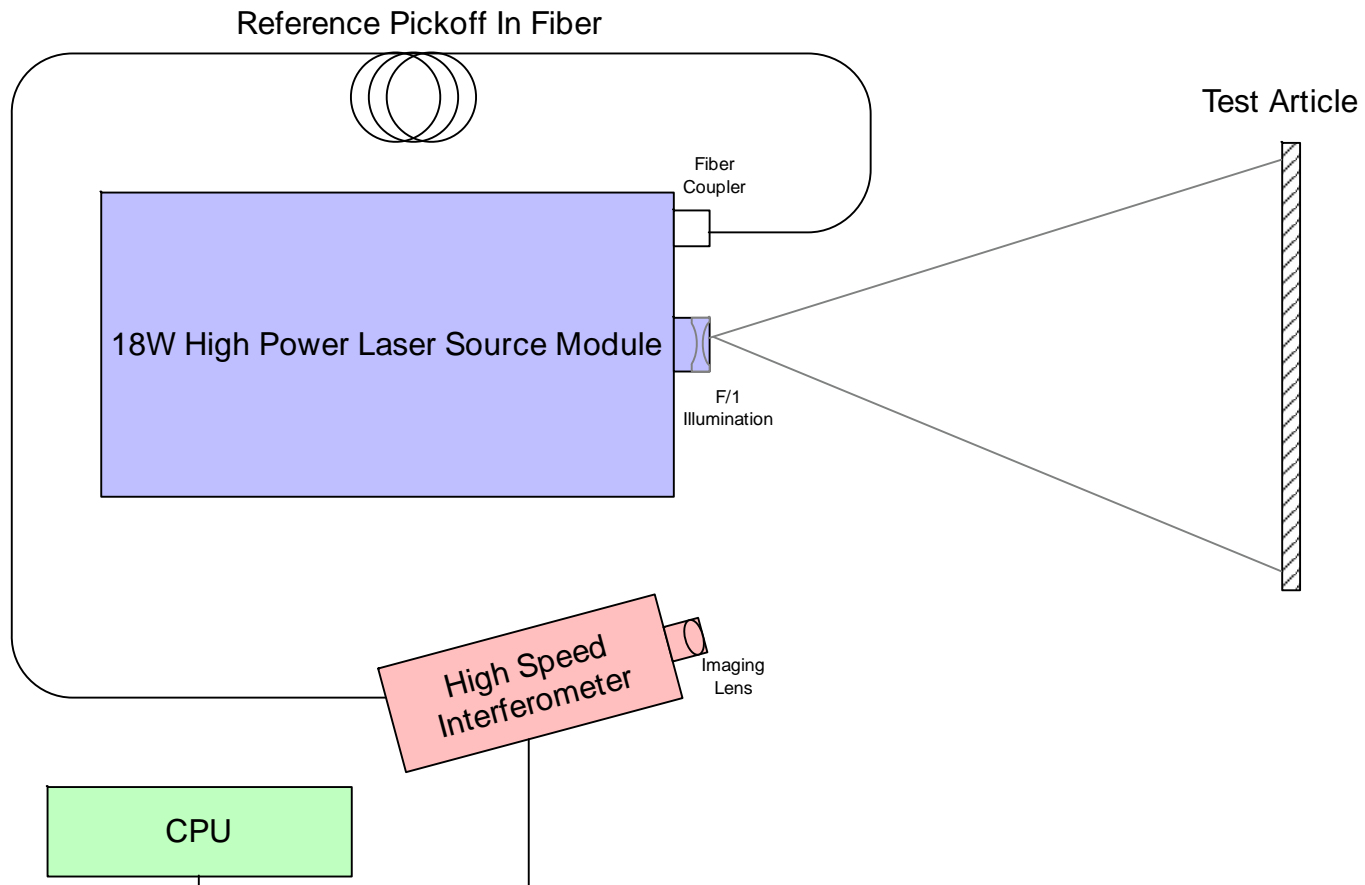


100's nm/days



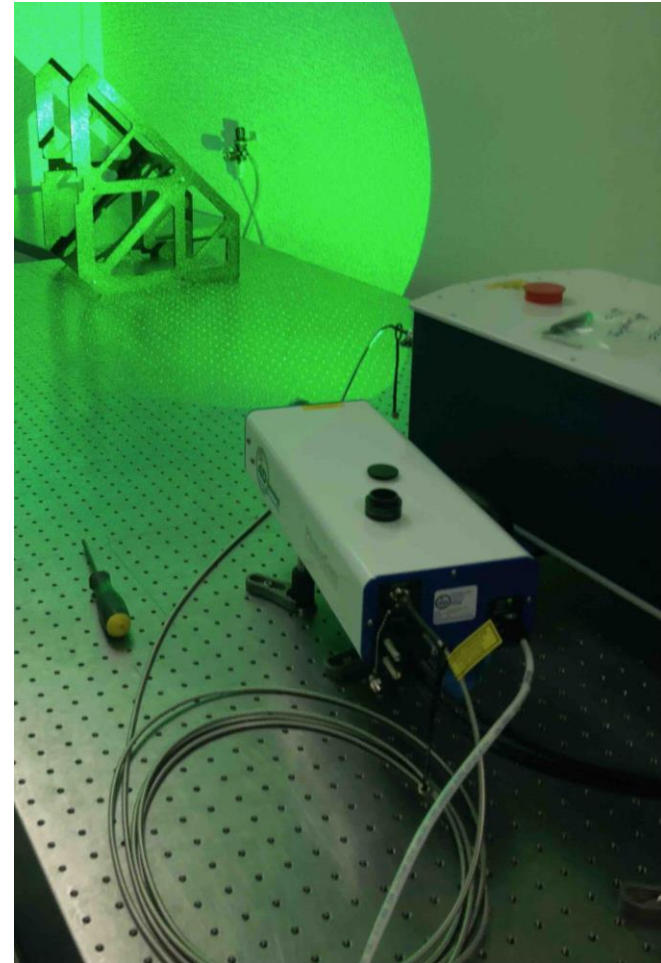
Babak Saif, et al. "Measurement of large cryogenic structures using a spatially phase-shifted digital speckle pattern interferometer," Appl. Opt. 47, (2008)

# High Speed ESPI Layout



# High Speed ESPI Status & Images

- ▶ System Build Complete
- ▶ Software Release  
Candidate in Testing
- ▶ Capability Evaluation in  
Process
- ▶ Quality Testing This Month

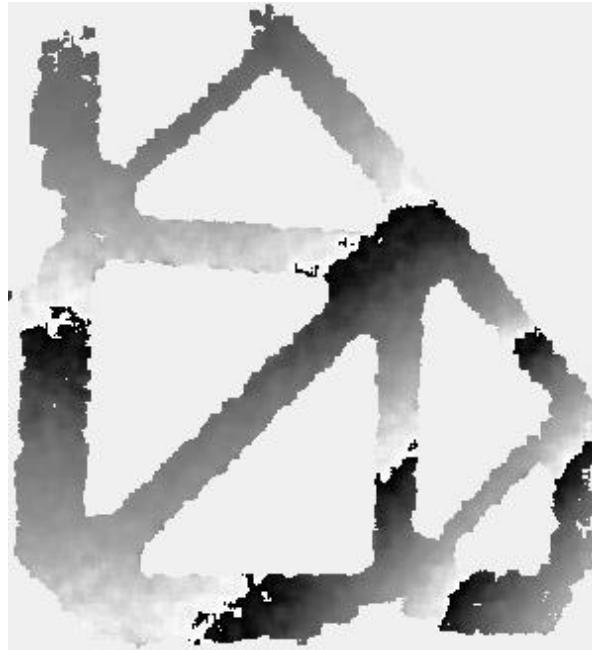


# Measurement of Anodized AL Support Structure

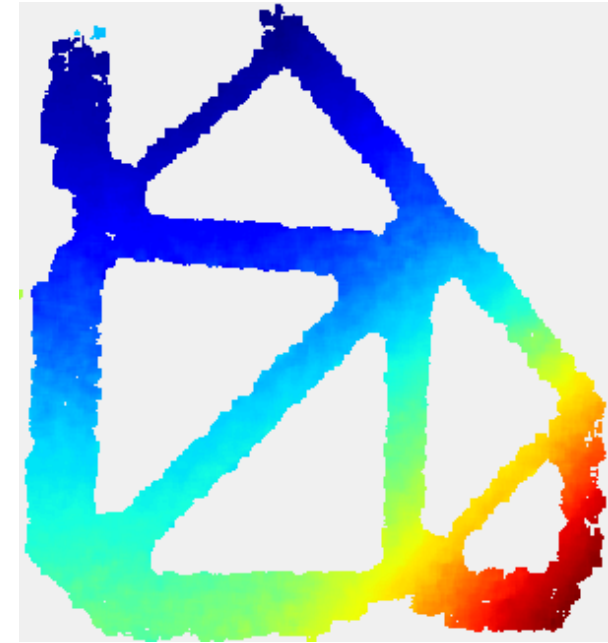
Interference Pattern

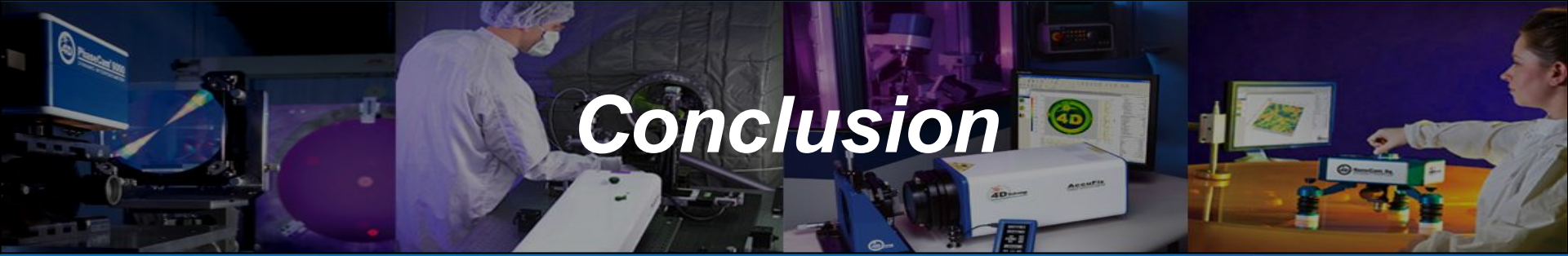


Wrapped Phase



Surface Change





# Conclusion

- ▶ High Speed Interferometry On JWST
  - ▶ Uses Dynamic Interferometer
  - ▶ Preliminary Tests Measured Dynamic Effects On the Level of Tens of Pico-meters
- ▶ Next Generation
  - ▶ Combine High Speed Interferometer with ESPI Measurements
  - ▶ Initial System Build Complete
  - ▶ System Evaluation in Process